

Search Notes

Application/Control No.

10/052,411

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	229	2/3/2007	EB
375	232	2/3/2007	EB
375	233	2/3/2007	EB
375	234	2/3/2007	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	2/3/2007	EB